

corrections for Figures 1, 2, 6 and 7, including any additional changes in response to form PTO-948, when the application is allowed by Examiner.

IN THE CLAIMS

Please amend claims 1 and 15 as follows:

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1. (Amended) A scanning force microscope probe, comprising:  
a cantilever having a first end and a second end; and  
a reflective structure included on the cantilever such that at least a portion of light  
that is directed substantially through free space to the cantilever in a first direction having  
a directional component from the first end to the second end is reflected from the  
reflective structure substantially through free space in a second direction having a  
directional component from the second end to the first end.

15. (Amended) A method of detecting motion of a scanning force microscope  
probe cantilever, the cantilever having a first end and a second end, the method  
comprising:

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directing light to the cantilever in a first direction substantially through free space  
having a directional component from the first end to the second end of the cantilever;  
reflecting at least a portion of the light from the cantilever in a second direction  
substantially through free space having a directional component from the second end to  
the first end of the cantilever; and  
receiving the portion of the light reflected from the cantilever to detect motion of  
the cantilever.